

*Electronic Supplementary Information (ESI) for the manuscript:*  
**Assessing the stability of Cd<sub>3</sub>As<sub>2</sub> Dirac semimetal in humid environments: the influence of defects, steps and surface oxidation**

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NOTE: SUPPORTING VIDEOS ARE ALSO AVAILABLE TO VISUALIZE VIBRATIONAL MODES

## S1. X-ray diffraction (XRD)

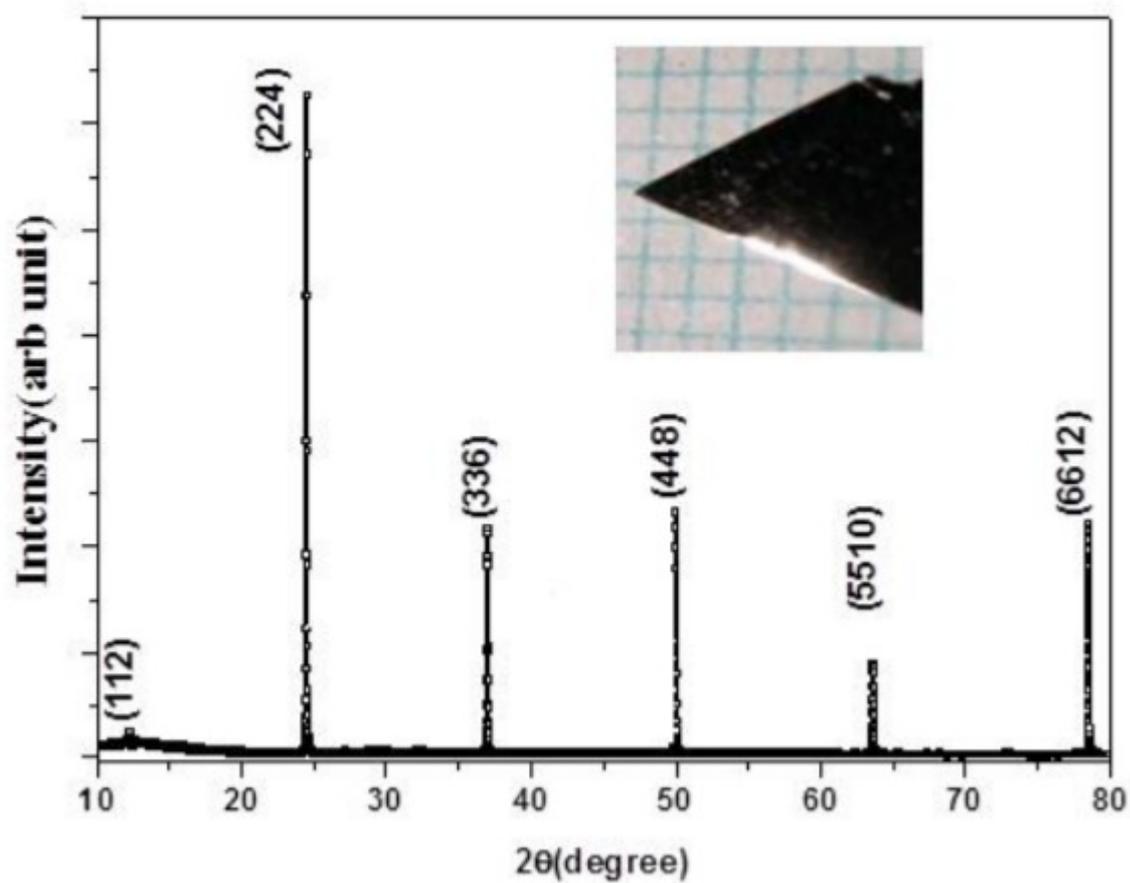
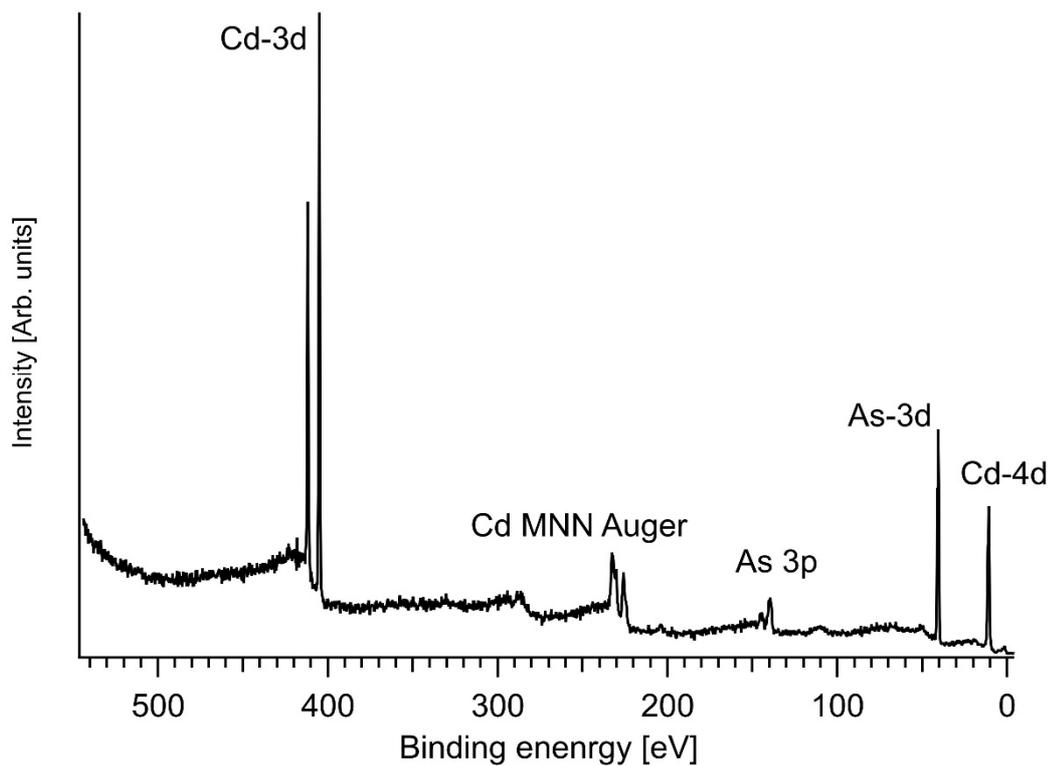
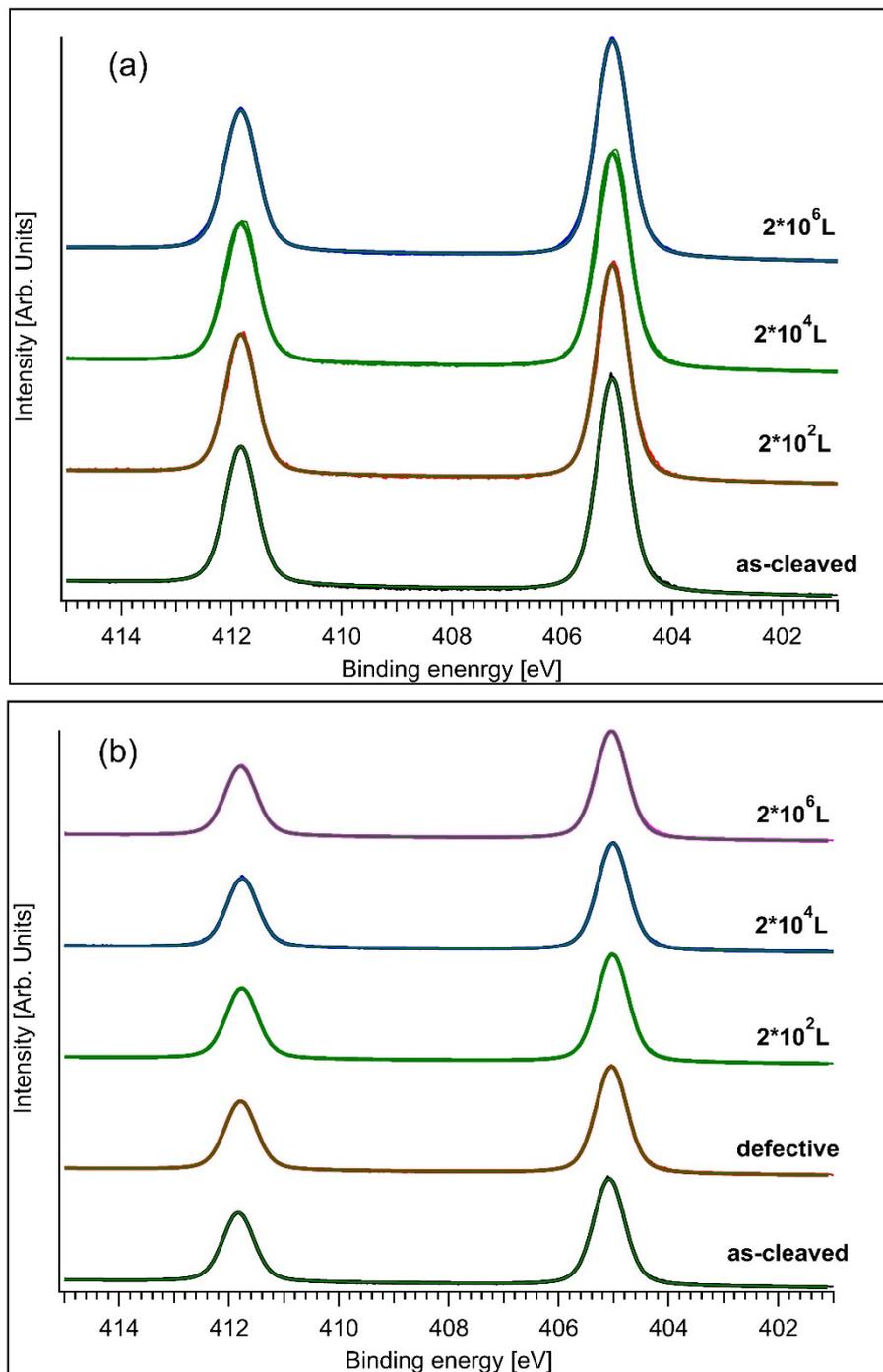


Figure S1. XRD pattern of (112)-oriented foils of Cd<sub>3</sub>As<sub>2</sub>

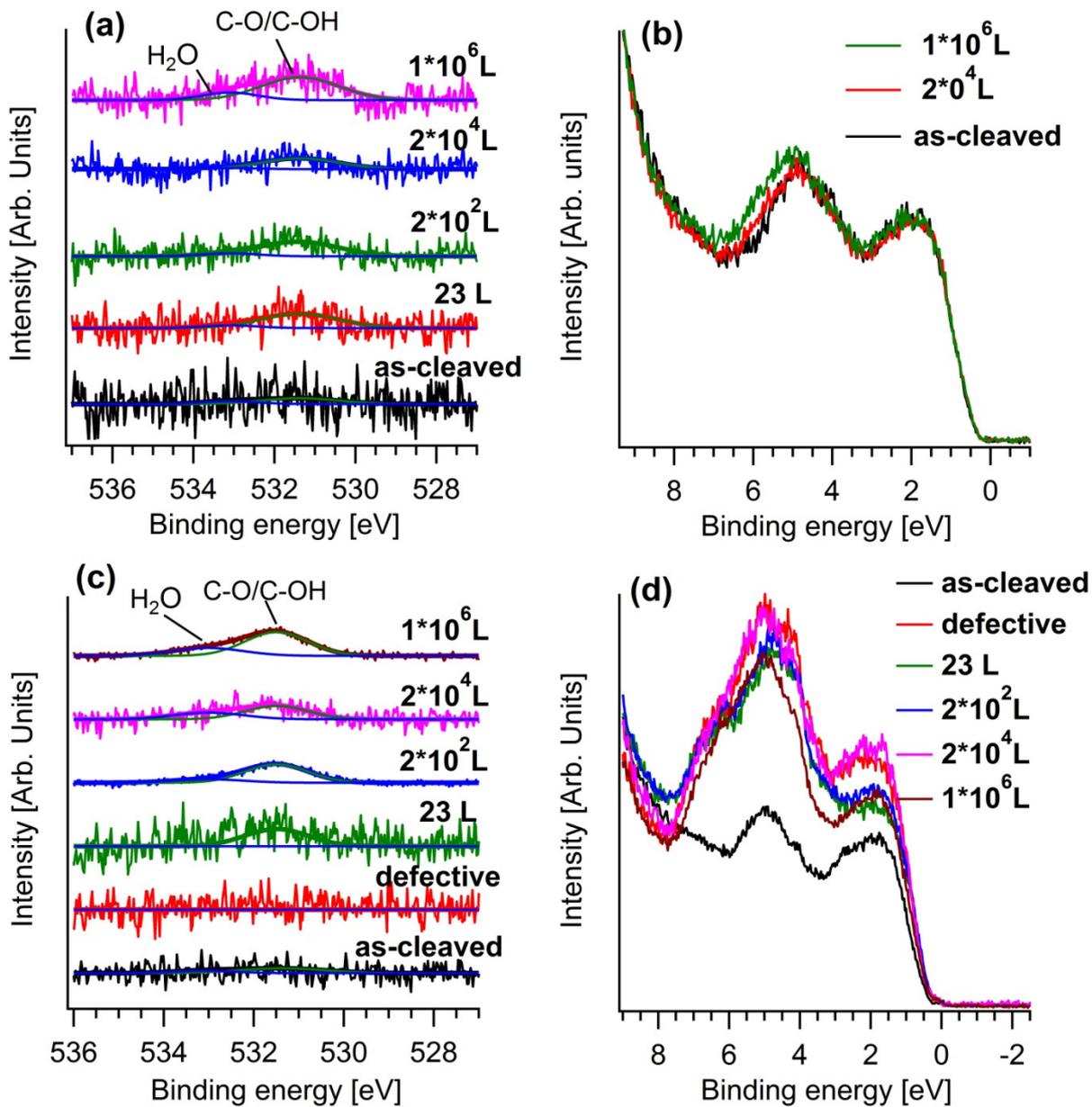
## S2. X-Ray photoemission spectroscopy (XPS)



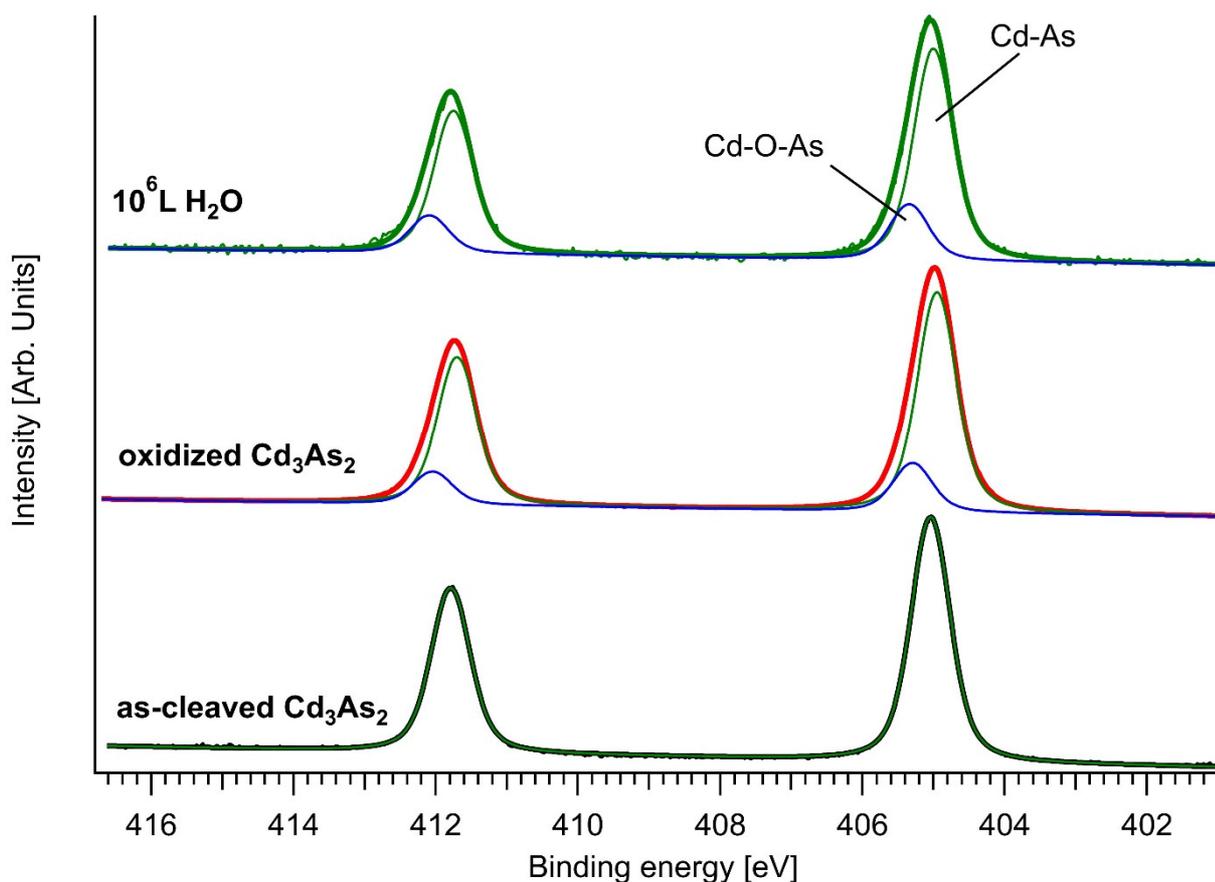
**Figure S2.** Survey spectrum of as-cleaved  $\text{Cd}_3\text{As}_2$  measured with a photon energy of 610 eV. Notably, no relevant signal from O-1s and C-1s is recorded, thus demonstrating the surface cleanliness.



**Figure S3.** Cd-3d core-level for as-cleaved Cd<sub>3</sub>As<sub>2</sub> (a) and defective Cd<sub>3</sub>As<sub>2</sub> surfaces (b) exposed to 23 L, 2·10<sup>2</sup> L, 2.3·10<sup>4</sup> L and 1.1·10<sup>6</sup> L of H<sub>2</sub>O. The incident photon energy is 596 eV.



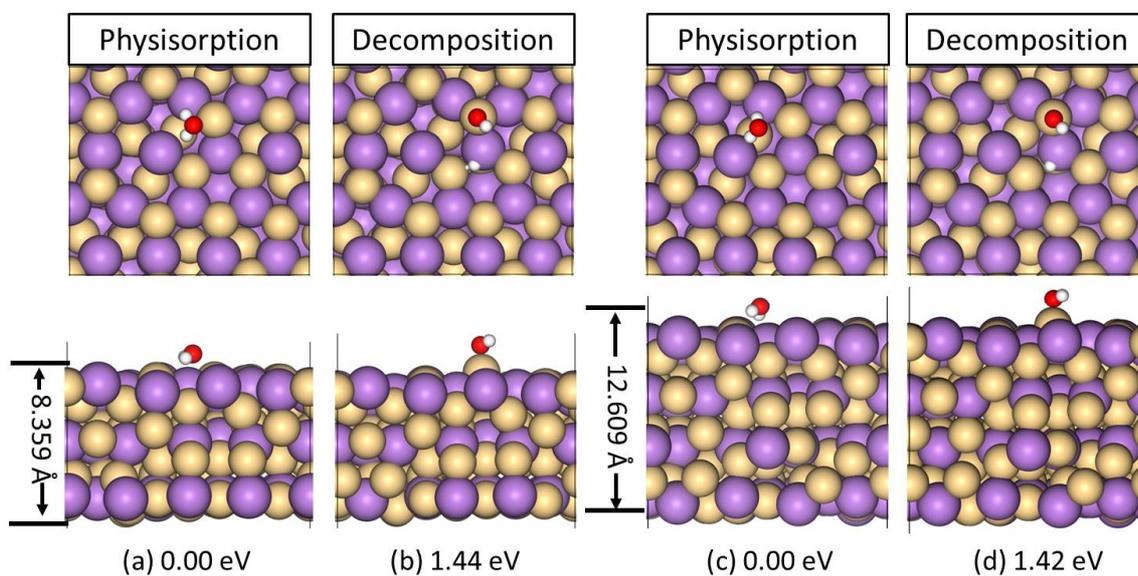
**Figure S4.** O-1s and valence band spectra for as-cleaved Cd<sub>3</sub>As<sub>2</sub> (top) and defective Cd<sub>3</sub>As<sub>2</sub> surfaces (bottom) exposed to 23 L, 2·10<sup>2</sup> L, 2.3·10<sup>4</sup> L and 1.1·10<sup>6</sup> L of H<sub>2</sub>O. The incident photon energy used to measure O-1s is 596 eV, while the valence band was measured with a photon energy of 190 eV.



**Figure S5.** Cd-3d for as-cleaved  $\text{Cd}_3\text{As}_2$  (black curve), oxidized  $\text{Cd}_3\text{As}_2$  obtained by exposing the as-cleaved sample to  $5 \cdot 10^4 \text{ L}$  of  $\text{O}_2$  (red curve) and the same oxidized surface after exposure to  $10^6 \text{ L}$  (green curve) of  $\text{H}_2\text{O}$  at room temperature. The incident photon energy is 610 eV. After  $\text{O}_2$  exposure the main Cd-As component is slightly down-shifted due to oxygen intercalation and a new doublet with  $J=5/2$  at  $\text{BE} \sim 405.3 \text{ eV}$  ascribed to hybrid Cd-O-As bonds appears.



**Figure S6.** Low-energy electron diffraction (LEED) image of a freshly cleaved  $\text{Cd}_3\text{As}_2$  crystal. The first-order diffraction spots are arranged in the pseudo-hexagonal symmetry characteristic of the (112) natural cleavage plane. Blue hexagons denote the surface Brillouin zone (SBZ). Taken from our previous publication on Ref. <sup>1</sup>. (Copyright American Physical Society, 2018)



**Figure S7.** (a) Top and (c) side views of the adsorption configuration for  $\text{H}_2\text{O}$  adsorption at pristine  $\text{Cd}_3\text{As}_2(112)$  surface with different thickness, respectively. Panels (b) and (d) show the H and OH fragments adsorbed at pristine  $\text{Cd}_3\text{As}_2(112)$  surface with different thickness, respectively. Purple, brown, white and red balls denote As, Cd, H and O atoms, respectively.

1. S. Roth, H. Lee, A. Sterzi, M. Zacchigna, A. Politano, R. Sankar, F. Chou, G. Di Santo, L. Petaccia, O. Yazyev and A. Crepaldi, *Phys. Rev. B*, 2018, **97**, 165439.